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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	51
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 15x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f303r6t6

2 Description

The STM32F303x6/8 family incorporates the high-performance ARM® Cortex®-M4 32-bit RISC core operating at up to 72 MHz frequency embedding a floating point unit (FPU), high-speed embedded memories (up to 64 Kbytes of Flash memory, 12 Kbytes of SRAM), and an extensive range of enhanced I/Os and peripherals connected to two APB buses.

The STM32F303x6/8 microcontrollers offer up to two fast 12-bit ADCs (5 Msps), up to three ultra-fast comparators, an operational amplifier, three DAC channels, a low-power RTC, one general-purpose, 32-bit timer, one timer dedicated to motor control, and four general-purpose, 16-bit timers. They also feature standard and advanced communication interfaces: one I^2C, one SPI, up to three USARTs and one CAN.

The STM32F303x6/8 family operates in the –40 to +85 °C and –40 to +105 °C temperature ranges from a 2.0 to 3.6 V power supply. A comprehensive set of power-saving modes allows the design of low-power applications.

The STM32F303x6/8 family offers devices in 32, and 64-pin packages.

Depending on the device chosen, different sets of peripherals are included.

remains in reset mode when the monitored supply voltage is below a specified threshold, $V_{POR/PDR}$, without the need for an external reset circuit.

- The POR monitors only the V_{DD} supply voltage. During the startup phase it is required that V_{DDA} should arrive first and be greater than or equal to V_{DD}.
- The PDR monitors both the V_{DD} and V_{DDA} supply voltages, however the V_{DDA} power supply supervisor can be disabled (by programming a dedicated Option bit) to reduce the power consumption if the application design ensures that V_{DDA} is higher than or equal to V_{DD}.

The device features an embedded programmable voltage detector (PVD) that monitors the V_{DD} power supply and compares it to the V_{PVD} threshold. An interrupt can be generated when V_{DD} drops below the V_{PVD} threshold and/or when V_{DD} is higher than the V_{PVD} threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

3.4.3 Voltage regulator

The regulator has three operation modes: main (MR), low-power (LPR), and power-down.

- The MR mode is used in the nominal regulation mode (Run)
- The LPR mode is used in Stop mode.
- The power-down mode is used in Standby mode: the regulator output is in high impedance, and the kernel circuitry is powered down thus inducing zero consumption.

The voltage regulator is always enabled after reset. It is disabled in Standby mode.

3.4.4 Low-power modes

The STM32F303x6/8 supports three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep mode**

  In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

- **Stop mode**

  Stop mode achieves the lowest power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low-power mode.

  The device can be woken up from Stop mode by any of the EXTI line. The EXTI line source can be one of the 16 external lines, the PVD output, the RTC alarm, COMPx, I^2C or USARTx.

- **Standby mode**

  The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the Backup domain and Standby circuitry.

  The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pin, or an RTC alarm occurs.

Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.

3.7 General-purpose inputs/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions. All GPIOs are high current capable except for analog inputs.

The I/Os alternate function configuration can be locked if needed, following a specific sequence to avoid spurious writing to the I/Os registers.

Fast I/O handling allows I/O toggling up to 36 MHz.

3.8 Direct memory access (DMA)

The flexible general-purpose DMA is able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. The DMA controller supports circular buffer management, avoiding the generation of interrupts when the controller reaches the end of the buffer.

Each of the 7 DMA channels is connected to dedicated hardware DMA requests, with software trigger support for each channel. Configuration is done by software and transfer sizes between source and destination are independent.

The DMA can be used with the main peripherals: SPI, I^2C, USART, general-purpose timers, DAC and ADC.

3.9 Interrupts and events

3.9.1 Nested vectored interrupt controller (NVIC)

The STM32F303x6/8 devices embed a nested vectored interrupt controller (NVIC) able to handle up to 60 interrupt channels, that can be masked and 16 priority levels.

The NVIC benefits are the following:

- Closely coupled NVIC gives low latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Closely coupled NVIC core interface
- Allows early processing of interrupts
- Processing of late arriving higher priority interrupts
- Support for tail chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

The NVIC hardware block provides flexible interrupt management features with minimal interrupt latency.

3.9.2 Extended interrupt/event controller (EXTI)

The external interrupt/event controller consists of 27 edge detector lines used to generate interrupt/event requests and wake-up the system. Each line can be independently configured to select the trigger event (rising edge, falling edge, both) and can be masked

Figure 6. LQFP64 pinout

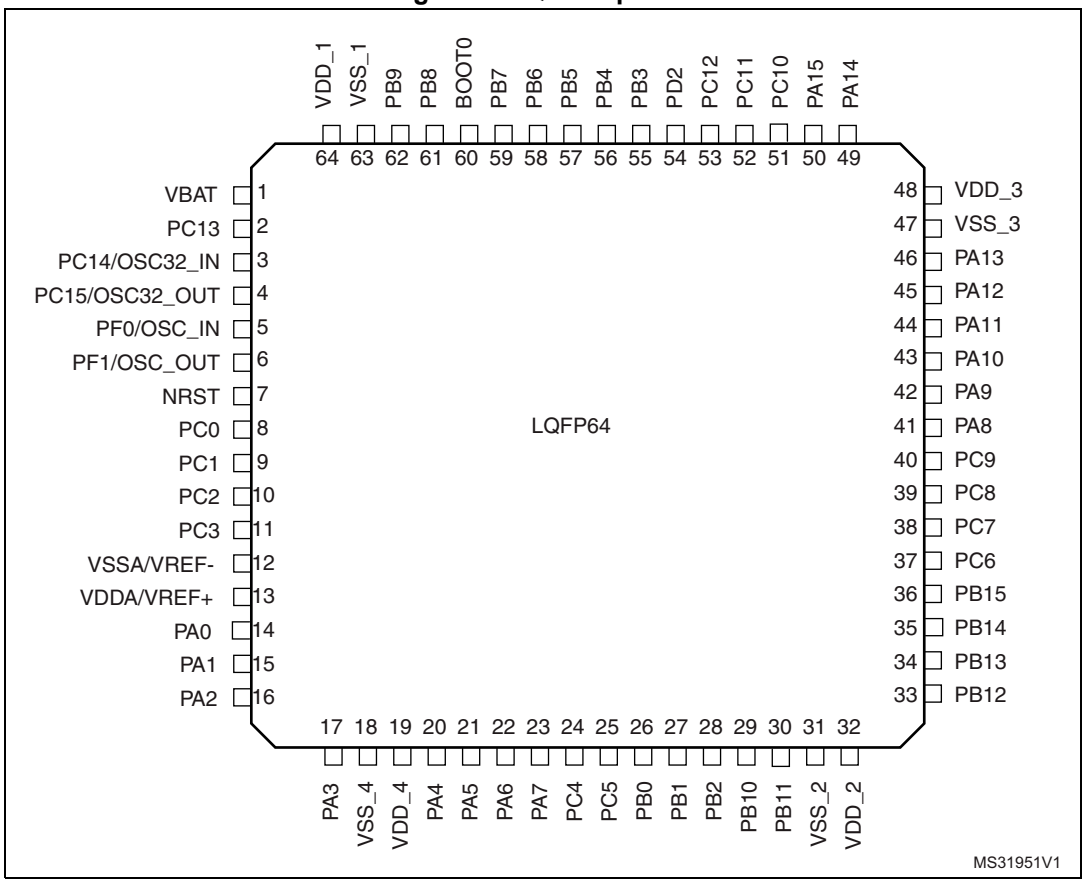


Table 15. Alternate functions

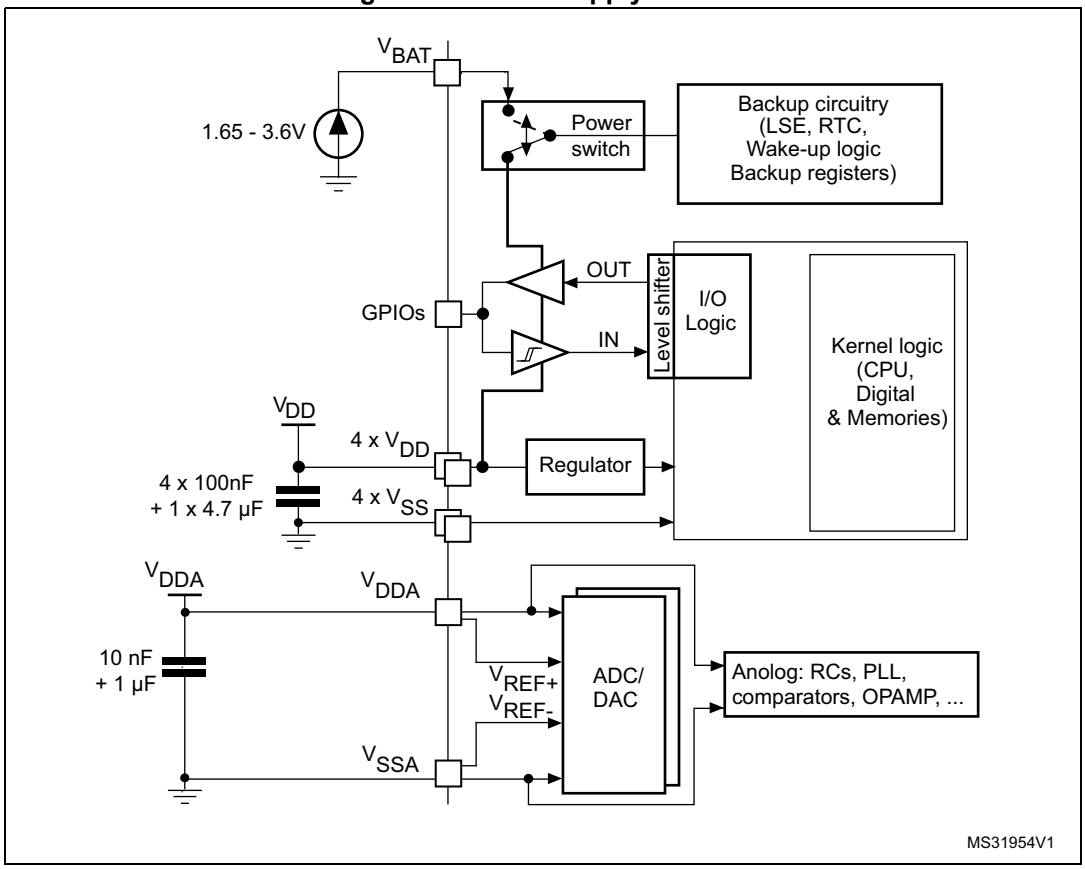
Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		SYS_AF	TIM2/TIM15/ TIM16/TIM17/ EVENT	TIM1/TIM3/ TIM15/ TIM16	TSC	I2C1/TIM1	SPI1/Infrared	TIM1/Infrared	USART1/USART2/USART3/ GPCOMP6	GPCOMP2/ GPCOMP4/ GPCOMP6	CAN/TIM1/ TIM15	TIM2/TIM3 /TIM17	TIM1	TIM1	OPAMP2	-	EVENT
Port A	PA0	-	TIM2_CH1/TI M2_ETR	-	TSC_G1_IO1	-	-	-	USART2_CTS	-	-	-	-	-	-	-	EVENTOUT
	PA1	-	TIM2_CH2	-	TSC_G1_IO2	-	-	-	USART2_RTS _DE	-	TIM15_CH1N	-	-	-	-	-	EVENTOUT
	PA2	-	TIM2_CH3	-	TSC_G1_IO3	-	-	-	USART2_TX	COMP2_OUT	TIM15_CH1	-	-	-	-	-	EVENTOUT
	PA3	-	TIM2_CH4	-	TSC_G1_IO4	-	-	-	USART2_RX	-	TIM15_CH2	-	-	-	-	-	EVENTOUT
	PA4	-	-	TIM3_CH2	TSC_G2_IO1	-	SPI1_NSS	-	USART2_CK	-	-	-	-	-	-	-	EVENTOUT
	PA5	-	TIM2_CH1/TI M2_ETR	-	TSC_G2_IO2	-	SPI1_SCK	-	-	-	-	-	-	-	-	-	EVENTOUT
	PA6	-	TIM16_CH1	TIM3_CH1	TSC_G2_IO3	-	SPI1_MISO	TIM1_BKIN	-	-	-	-	-	-	-	-	EVENTOUT
	PA7	-	TIM17_CH1	TIM3_CH2	TSC_G2_IO4	-	SPI1_MOSI	TIM1_CH1N	-	-	-	-	-	-	-	-	EVENTOUT
	PA8	MCO	-	-	-	-	-	TIM1_CH1	USART1_CK	-	-	-	-	-		v	EVENTOUT
	PA9	-	-	-	TSC_G4_IO1	-	-	TIM1_CH2	USART1_TX	-	TIM15_BKIN	TIM2_CH3	-	-		-	EVENTOUT
	PA10	-	TIM17_BKIN	-	TSC_G4_IO2	-	-	TIM1_CH3	USART1_RX	COMP6_OUT	-	TIM2_CH4	-	-		-	EVENTOUT
	PA11	-	-	-	-	-	-	TIM1_CH1N	USART1_CTS	-	CAN_RX	-	TIM1_CH4	TIM1_BKIN2		-	EVENTOUT
	PA12	-	TIM16_CH1	-	-	-	-	TIM1_CH2N	USART1_RTS _DE	COMP2_OUT	CAN_TX	-	TIM1_ETR	-		-	EVENTOUT
	PA13	JTMS/SWDAT	TIM16_CH1N	-	TSC_G4_IO3	-	IR_OUT	-	USART3_CTS	-	-	-	-	-	-	-	EVENTOUT
	PA14	JTCK/SWCLK	-	-	TSC_G4_IO4	I2C1_SDA	-	TIM1_BKIN	USART2_TX	-	-	-	-	-	-	-	EVENTOUT
	PA15	JTDI	TIM2_CH1/ TIM2_ETR	-	TSC_SYNC	I2C1_SCL	SPI1_NSS	-	USART2_RX	-	TIM1_BKIN	-	-	-		-	EVENTOUT
Port B	PB0	-	-	TIM3_CH3	TSC_G3_IO2	-	-	TIM1_CH2N	-	-	-	-	-	-	-	-	EVENTOUT
	PB1	-	-	TIM3_CH4	TSC_G3_IO3	-	-	TIM1_CH3N	-	COMP4_OUT	-	-	-	-		-	EVENTOUT
	PB2	-	-	-	TSC_G3_IO4	-	-	-	-	-	-	-	-	-		-	EVENTOUT
	PB3	JTDO/TRACE SWO	TIM2_CH2	-	TSC_G5_IO1	-	SPI1_SCK	-	USART2_TX	-	-	TIM3_ETR	-			-	EVENTOUT
	PB4	NJTRST	TIM16_CH1	TIM3_CH1	TSC_G5_IO2	-	SPI1_MISO	-	USART2_RX	-	-	TIM17_BK IN	-	-		-	EVENTOUT
	PB5	-	TIM16_BKIN	TIM3_CH2	-	I2C1_SMBA	SPI1_MOSI	-	USART2_CK	-	-	TIM17_CH 1	-	-		-	EVENTOUT
	PB6	-	TIM16_CH1N	-	TSC_G5_IO3	I2C1_SCL	-	-	USART1_TX	-	-	-	-			-	EVENTOUT
	PB7	-	TIM17_CH1N	-	TSC_G5_IO4	I2C1_SDA	-	-	USART1_RX	-	-	TIM3_CH4	-	-		-	EVENTOUT
	PB8	-	TIM16_CH1	-	TSC_SYNC	I2C1_SCL	-	-	USART3_RX	-	CAN_RX	-	-	TIM1_BKIN		-	EVENTOUT
	PB9	-	TIM17_CH1	-	-	I2C1_SDA	-	IR_OUT	USART3_TX	COMP2_OUT	CAN_TX	-	-	-		-	EVENTOUT

Table 16. STM32F303x6/8 peripheral register boundary addresses (continued)

Bus	Boundary address	Size (bytes)	Peripheral
APB1	0x4000 9800 - 0x4000 9BFF	1 K	DAC2
	0x4000 7800 - 0x4000 97FF	8 K	Reserved
	0x4000 7400 - 0x4000 77FF	1 K	DAC1
	0x4000 7000 - 0x4000 73FF	1 K	PWR
	0x4000 6800 - 0x4000 6FFF	2 K	Reserved
	0x4000 6400 - 0x4000 67FF	1 K	bxCAN
	0x4000 5800 - 0x4000 63FF	3 K	Reserved
	0x4000 5400 - 0x4000 57FF	1 K	I2C1
	0x4000 4C00 - 0x4000 53FF	2 K	Reserved
	0x4000 4800 - 0x4000 4BFF	1 K	USART3
	0x4000 4400 - 0x4000 47FF	1 K	USART2
	0x4000 3400 - 0x4000 43FF	2 K	Reserved
	0x4000 3000 - 0x4000 33FF	1 K	IWDG
	0x4000 2C00 - 0x4000 2FFF	1 K	WWDG
	0x4000 2800 - 0x4000 2BFF	1 K	RTC
	0x4000 1800 - 0x4000 27FF	4 K	Reserved
	0x4000 1400 - 0x4000 17FF	1 K	TIM7
	0x4000 1000 - 0x4000 13FF	1 K	TIM6
	0x4000 0800 - 0x4000 0FFF	2 K	Reserved
	0x4000 0400 - 0x4000 07FF	1 K	TIM3
	0x4000 0000 - 0x4000 03FF	1 K	TIM2
-	0x2000 3000 - 3FFF FFFF	~512 M	Reserved
-	0x2000 0000 - 0x2000 2FFF	12 K	SRAM
-	0x1FFF F800 - 0x1FFF FFFF	2 K	Option bytes
-	0x1FFF D800 - 0x1FFF F7FF	8 K	System memory
-	0x1000 2000 - 0x1FFF D7FF	~256 M	Reserved
-	0x1000 0000 - 0x1000 0FFF	4 K	CCM RAM
-	0x0804 0000 - 0x0FFF FFFF	~128 M	Reserved
-	0x0800 0000 - 0x0800 FFFF	64 K	Main Flash memory
-	0x0004 0000 - 0x07FF FFFF	~128 M	Reserved
-	0x0000 000 - 0x0000 FFFF	64 K	Main Flash memory, system memory or SRAM depending on BOOT configuration

6.1.6 Power-supply scheme

Figure 10. Power-supply scheme



Caution: Each power-supply pair (V_{DD}/V_{SS}, V_{DDA}/V_{SSA} etc..) must be decoupled with filtering ceramic capacitors as shown above. These capacitors must be placed as close as possible to, or below the appropriate pins on the underside of the PCB to ensure the good functionality of the device.

6.3.2 Operating conditions at power-up / power-down

The parameters given in *Table 21* are derived from tests performed under the ambient temperature condition summarized in *Table 20*.

Table 21. Operating conditions at power-up / power-down

Symbol	Parameter	Conditions	Min.	Max.	Unit
t_{VDD}	V_{DD} rise time rate	-	0	∞	µs/V
	V_{DD} fall time rate		20	∞	
t_{VDDA}	V_{DDA} rise time rate	-	0	∞	
	V_{DDA} fall time rate		20	∞	

6.3.3 Characteristics of the embedded reset and power-control block

The parameters given in *Table 22* are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 20*.

Table 22. Embedded reset and power control block characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$V_{POR/PDR}$(1)	Power on/power down reset threshold	Falling edge	1.8(2)	1.88	1.96	V
		Rising edge	1.84	1.92	2.0	V
$V_{PDRhyst}$(1)	PDR hysteresis	-	-	40	-	mV
$t_{RSTTEMPO}$(3)	POR reset temporization	-	1.5	2.5	4.5	ms

1. The PDR detector monitors V_{DD} and also V_{DDA} (if kept enabled in the option bytes). The POR detector monitors only V_{DD}.
2. The product behavior is guaranteed by design down to the minimum $V_{POR/PDR}$ value.
3. Guaranteed by design, not tested in production.

Table 35. Peripheral current consumption (continued)

Peripheral	Typical consumption(1)	Unit
	I_{DD}	
CAN	31.3	-
PWR	4.7	-
DAC	15.4	-
DAC2	8.6	-
SPI1	8.2	-

1. The power consumption of the analog part (I_{DDA}) of peripherals such as ADC, DAC, Comparators, OpAmp etc. is not included. Refer to the tables of characteristics in the subsequent sections.
2. BusMatrix is automatically active when at least one master is ON (CPU or DMA1).
3. The APBx bridge is automatically active when at least one peripheral is ON on the same bus.

Table 47. EMS characteristics

Symbol	Parameter	Conditions	Level/ Class
V_{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 3.3 V, LQFP100, T_A = +25°C, f_{HCLK} = 72 MHz conforms to IEC 61000-4-2	2B
V_{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V_{DD} and V_{SS} pins to induce a functional disturbance	V_{DD} = 3.3 V, LQFP100, T_A = +25°C, f_{HCLK} = 72 MHz conforms to IEC 61000-4-4	4A

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (control registers...)

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note *"Software techniques for improving microcontrollers EMC performance"* AN1015).

Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application is executed (toggling 2 LEDs through the I/O ports). This emission test is compliant with IEC 61967-2 standard which specifies the test board and the pin loading.

6.3.13 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard, 3 V-capable I/O pins) should be avoided during normal product operation. However, to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibility to I/O current injection

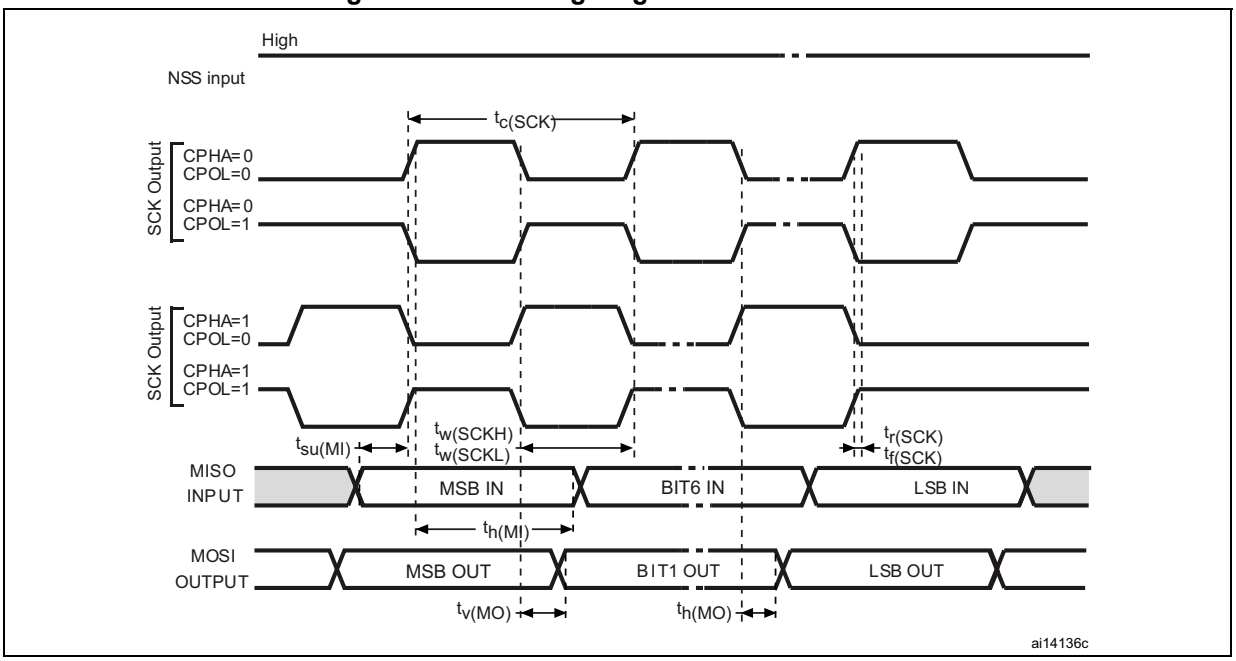
While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (higher than 5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of –5 µA/+0 µA range), or other functional failure (for example reset occurrence or oscillator frequency deviation). The test results are given in *Table 51: I/O current injection susceptibility*.

Table 51. I/O current injection susceptibility

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I_{INJ}	Injected current on BOOT0	– 0	NA	mA
	Injected current on PC0, PC1, PC2, PC3 (TTa pins) and PF1 pin (FT pin)	-0	+5	
	Injected current on PA0, PA1, PA2, PA3, PA4, PA5, PA6, PA7, PC4, PC5, PB0, PB1, PB2, PB12, PB13, PB14, PB15 with induced leakage current on other pins from this group less than -100 µA or more than +900 µA	-5	+5	
	Injected current on PB11, other TT, FT, and FTf pins	– 5	NA	
	Injected current on all other TC, TTa and RESET pins	– 5	+5	

Figure 26. SPI timing diagram - master mode(1)



1. Measurement points are done at $0.5V_{DD}$ and with external C_L = 30 pF.

CAN (controller area network) interface

Refer to *Section 6.3.14: I/O port characteristics* for more details on the input/output alternate function characteristics (CAN_TX and CAN_RX).

6.3.18 ADC characteristics

Unless otherwise specified, the parameters given in *Table 61* to *Table 64* are guaranteed by design, with conditions summarized in *Table 20*.

Table 61. ADC characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V_{DDA}	Analog supply voltage for ADC	-	2	-	3.6	V
I_{DDA}	ADC current consumption (*Figure 27*)	Single ended mode, 5 MSPS,	-	1011.3	1172.0	µA
		Single ended mode, 1 MSPS	-	214.7	322.3	
		Single ended mode, 200 KSPS	-	54.7	81.1	
		Differential mode,5 MSPS,	-	1061.5	1243.6	
		Differential mode, 1 MSPS	-	246.6	337.6	
		Differential mode, 200 KSPS	-	56.4	83.0	

Table 66. DAC characteristics (continued)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
DNL(3)	Differential non linearity Difference between two consecutive code-1LSB)	Given for a 10-bit input code DAC1 channel 1	-	-	±0.5	LSB
		Given for a 12-bit input code DAC1 channel 1	-	-	±2	LSB
		Given for a 10-bit input code DAC1 channel 2 & DAC2 channel 1	-	-	-0.75/+0.25	LSB
		Given for a 12-bit input code DAC1 channel 2 & DAC2 channel 1	-	-	-3/+1	LSB
INL(3)	Integral non linearity (difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 4095)	Given for a 10-bit input code	-	-	±1	LSB
		Given for a 12-bit input code	-	-	±4	LSB
Offset(3)	Offset error (difference between measured value at Code (0x800) and the ideal value = V_{DDA}/2)	-	-	-	±10	mV
		Given for a 10-bit input code at V_{DDA} = 3.6 V	-	-	±3	LSB
		Given for a 12-bit input code	-	-	±12	LSB
Gain error(3)	Gain error	Given for a 12-bit input code	-	-	±0.5	%
$t_{SETTLING}$(3)	Settling time (full scale: for a 12-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches final value ±1LSB	$C_{LOAD} \leq 50$ pF, $R_{LOAD} \geq 5$ kΩ	-	3	4	µs
Update rate(3)	Max frequency for a correct DAC_OUT change when small variation in the input code (from code i to i+1LSB)	$C_{LOAD} \leq 50$ pF, $R_{LOAD} \geq 5$ kΩ	-	-	1	MS/s
I_{skink}	Output sink current	DAC buffer ON Output level higher than 0.2 V	100	-	-	µA
t_{WAKEUP}(3)	Wakeup time from off state (Setting the ENx bit in the DAC Control register)	$C_{LOAD} \leq 50$ pF, $R_{LOAD} \geq 5$ kΩ	-	6.5	10	µs
PSRR+ (1)	Power supply rejection ratio (to V_{DDA}) (static DC measurement	No R_{LOAD}, C_{LOAD} = 50 pF	-	–67	–40	dB

1. Guaranteed by design, not tested in production.
2. Quiescent mode refers to the state of the DAC a keeping steady value on the output, so no dynamic consumption is involved.
3. Data based on characterization results, not tested in production.

6.3.22 Temperature sensor (TS) characteristics

Table 69. Temperature sensor (TS) characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit
T_L(1)	V_{SENSE} linearity with temperature	-	±1	±2	°C
Avg_Slope(1)	Average slope	4.0	4.3	4.6	mV/°C
V_{25}	Voltage at 25 °C	1.34	1.43	1.52	V
t_{START}(1)	Startup time	4	-	10	µs
T_{S_temp}(1)(2)	ADC sampling time when reading the temperature	2.2	-	-	µs

1. Guaranteed by design, not tested in production.
2. Shortest sampling time can be determined in the application by multiple iterations.

Table 70. Temperature sensor (TS) calibration values

Calibration value name	Description	Memory address
TS_CAL1	TS ADC raw data acquired at temperature of 30 °C, V_{DDA}= 3.3 V	0x1FFF F7B8 - 0x1FFF F7B9
TS_CAL2	TS ADC raw data acquired at temperature of 110 °C V_{DDA}= 3.3 V	0x1FFF F7C2 - 0x1FFF F7C3

6.3.23 V_{BAT} monitoring characteristics

Table 71. V_{BAT} monitoring characteristics

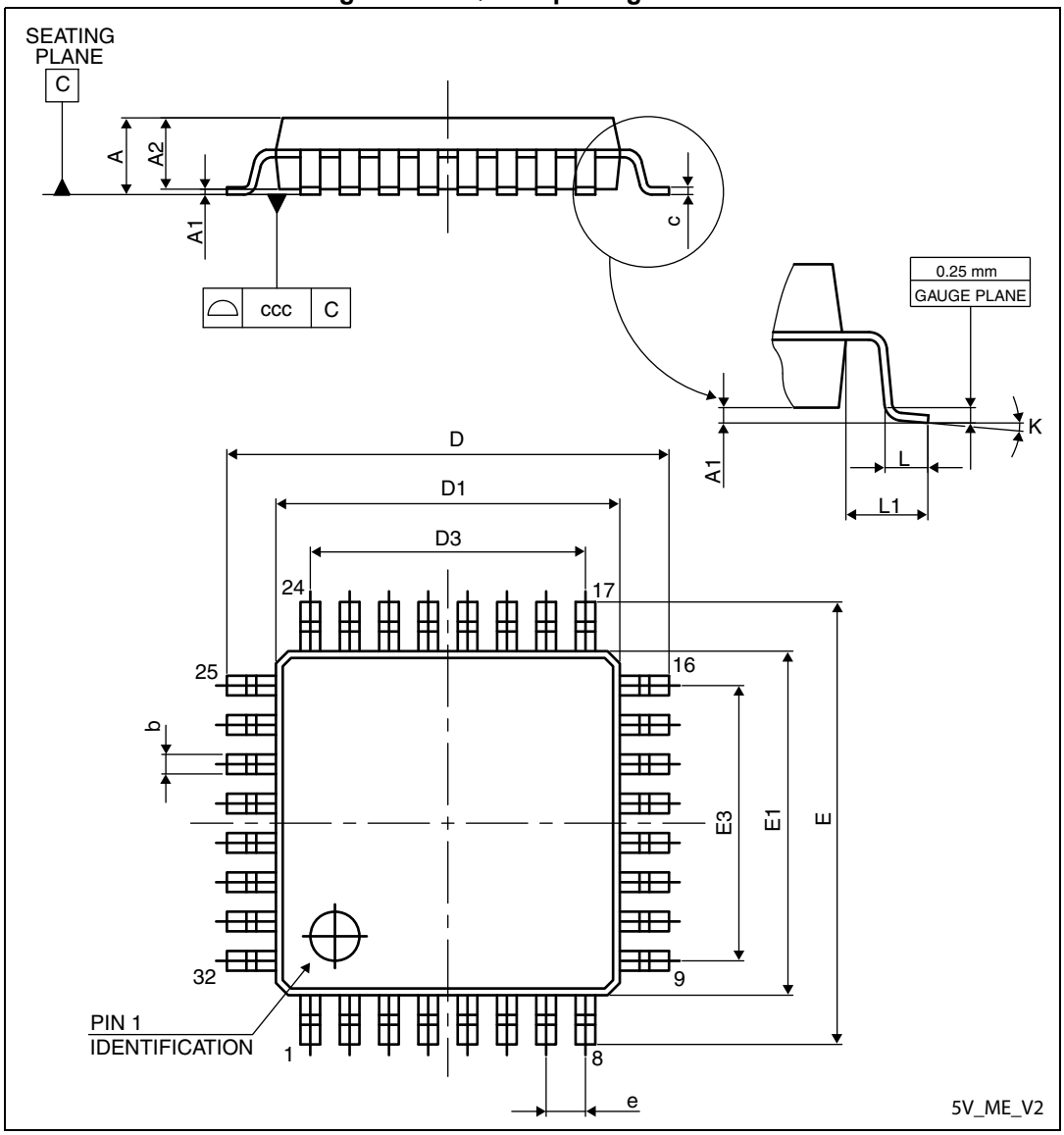
Symbol	Parameter	Min.	Typ.	Max.	Unit
R	Resistor bridge for V_{BAT}	-	50	-	KΩ
Q	Ratio on V_{BAT} measurement	-	2	-	-
Er(1)	Error on Q	-1	-	+1	%
T_{S_vbat}(1)(2)	ADC sampling time when reading the V_{BAT} 1mV accuracy	2.2	-	-	µs

1. Guaranteed by design, not tested in production.
2. Shortest sampling time can be determined in the application by multiple iterations.

7.2 LQFP32 package information

LQFP32 is a 32-pin, 7 x 7mm low-profile quad flat package.

Figure 33. LQFP32 package outline



1. Drawing is not to scale.

Table 72. LQFP32 mechanical data

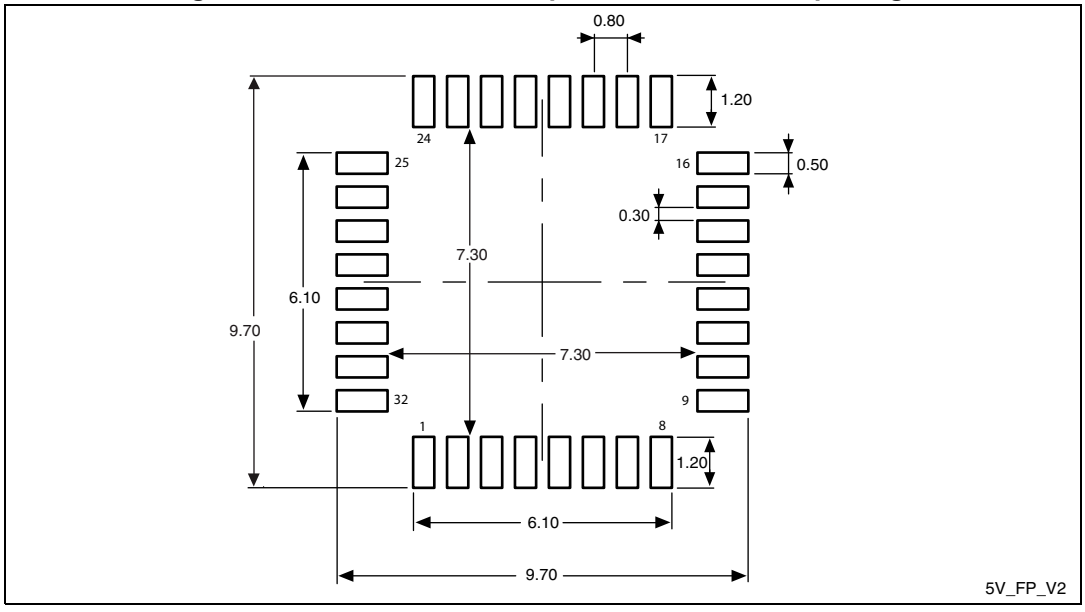
Symbol	Millimeters			Inches[1]		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571

Table 72. LQFP32 mechanical data (continued)

Symbol	Millimeters			Inches[1]		
	Min.	Typ.	Max.	Min.	Typ.	Max.
b	0.300	0.370	0.450	0.0118	0.0146	0.0177
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.600	-	-	0.2205	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.600	-	-	0.2205	-
e	-	0.800	-	-	0.0315	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0.0°	3.5°	7.0°	0.0°	3.5°	7.0°
ccc	-	-	0.100	-	-	0.0039

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 34. Recommended footprint for the LQFP32 package

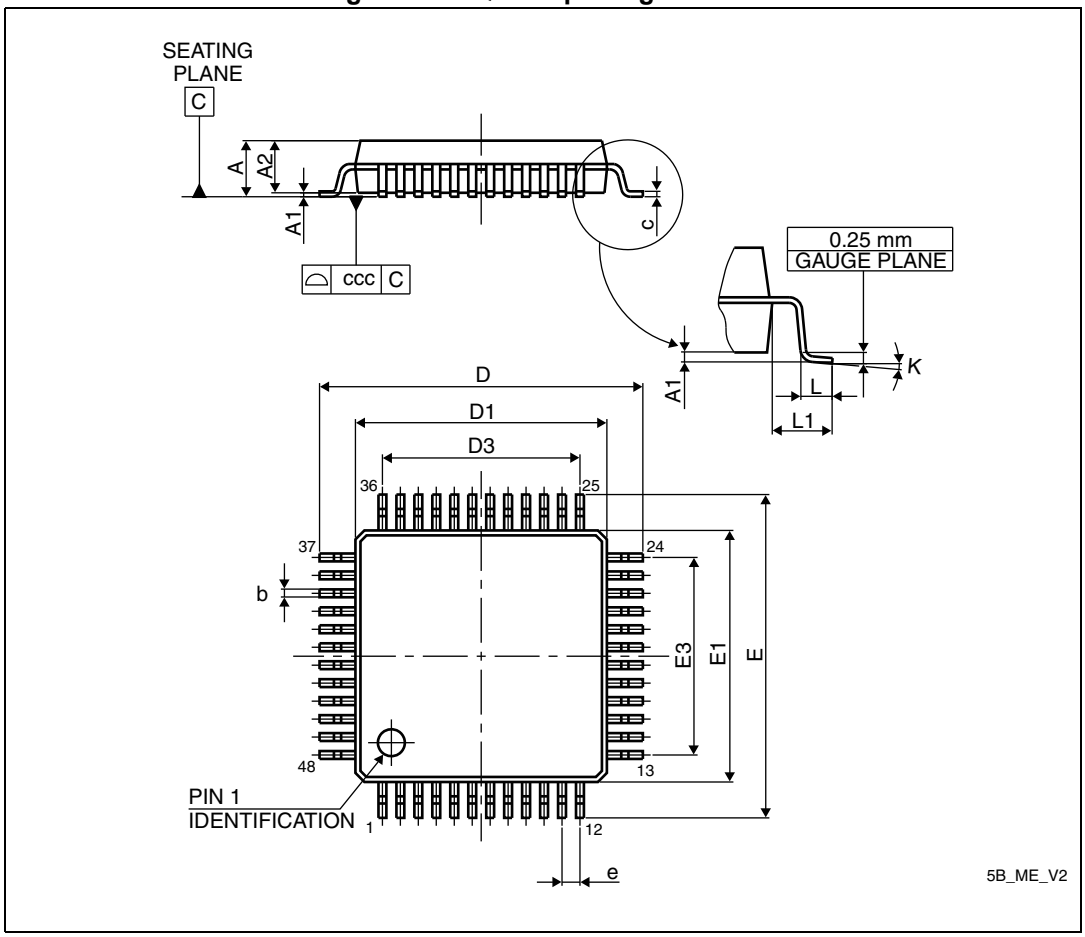


1. Drawing is not to scale.
2. Dimensions are expressed in millimeters.

7.3 LQFP48 package information

LQFP48 is a 48-pin, 7 x 7mm low-profile quad flat package.

Figure 36. LQFP48 package outline



1. Drawing is not to scale.

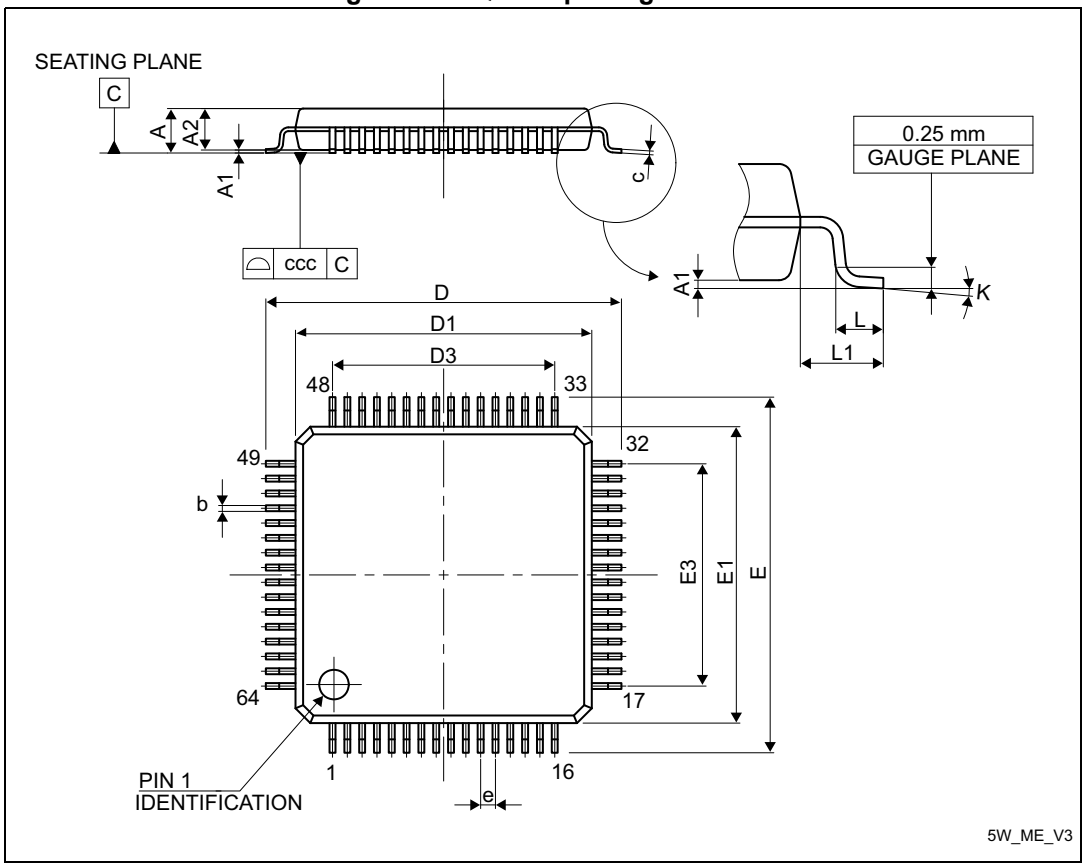
Table 73. LQFP48 package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.500	-	-	0.2165	-

7.4 LQFP64 package information

LQFP64 is a 64-pin, 10 x 10 mm low-profile quad flat package.

Figure 39. LQFP64 package outline



1. Drawing is not to scale.

Table 74. LQFP64 package mechanical data

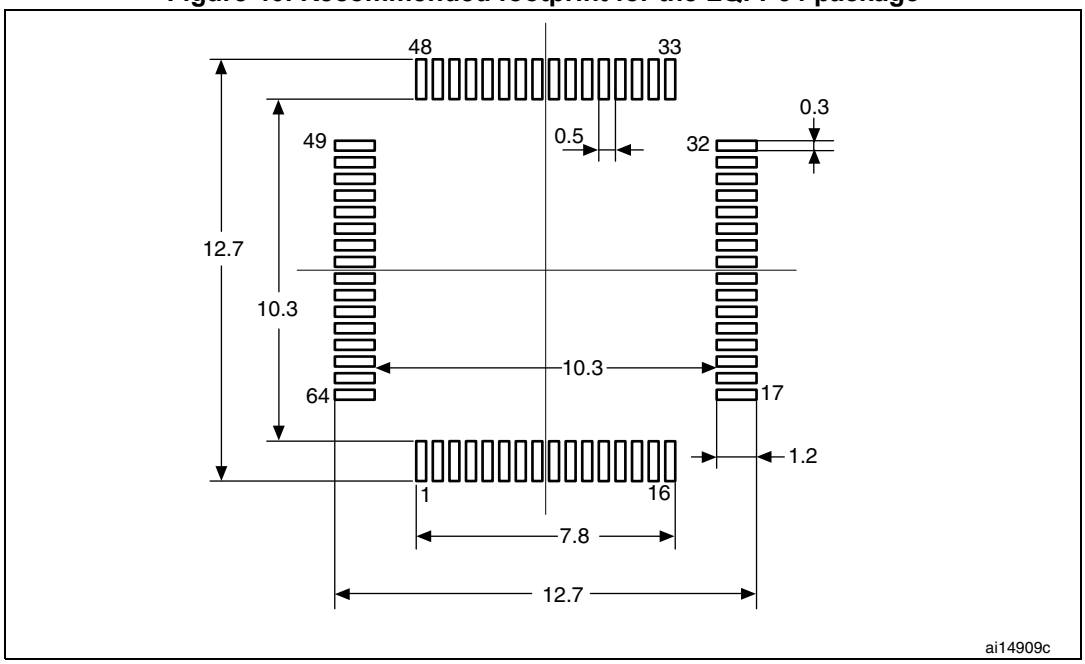
Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	11.800	12.000	-	-	0.4724	-
D1	9.800	10.000	-	-	0.3937	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-
e	-	0.500	-	-	0.0197	-

Table 74. LQFP64 package mechanical data (continued)

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
θ	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
N	Number of pins					
	64					

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 40. Recommended footprint for the LQFP64 package

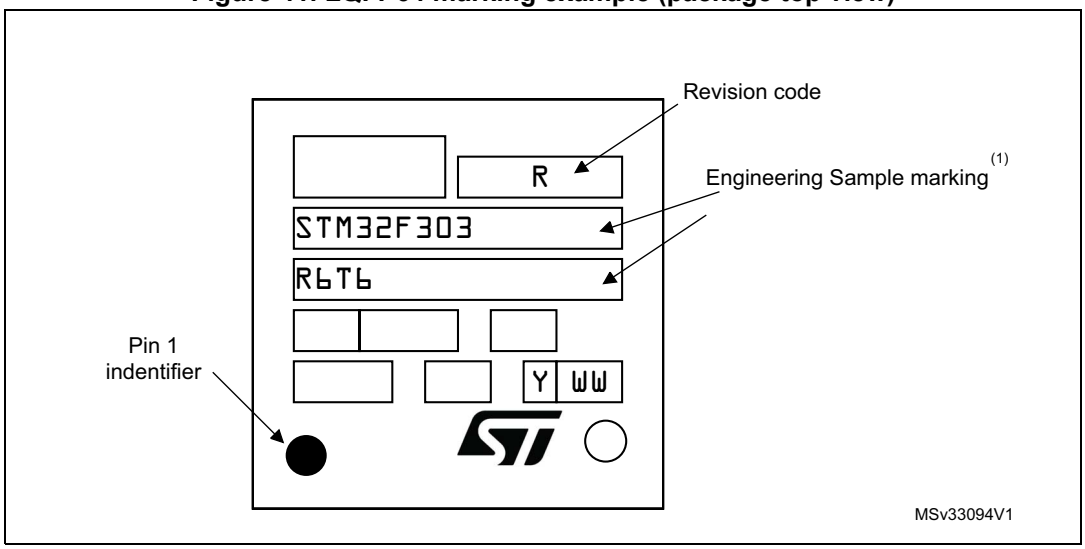


1. Drawing is not to scale.
2. Dimensions are in millimeters.

Device marking for LQFP64

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 41. LQFP64 marking example (package top view)



1. Parts marked as “ES”,”E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.